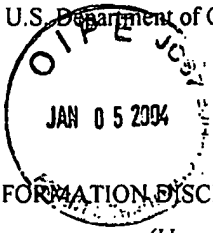
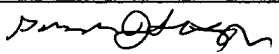
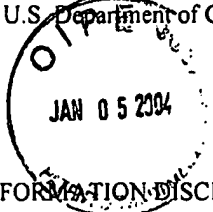


U.S. Department of Commerce, Patent and Trademark Office  INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	Application No.:	09/974,571
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	Group Art Unit:	2877
	Examiner Name:	Unknown
	Confirmation No.:	1003
	Attorney Docket No.:	BOX013 US

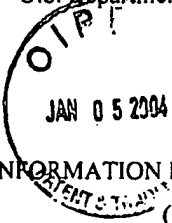
U.S. Patent Documents							
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
PD	1.	4,273,421	6/16/81	Gurtler	356	432	
PD	2.	4,854,710	8/8/89	Opsal et al.	356	432	
PD	3.	4,211,488	7/8/80	Kleinknecht	356	433	
PD	4.	5,379,109	1/3/95	Gaskill et al.	356	445	
PD	5.	6,489,801	12/3/02	Borden et al.	324	766	
PD	6.	5,966,019	10/12/99	Borden	324	752	
PD	7.	5,377,006	12/27/94	Nakata	356	349	
PD	8.	5,706,094	1/6/98	Maris	356	432	
PD	9.	6,118,533	9/12/00	Banet et al.	356	345	
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PD	11	6,426,644	7/30/02	Borden et al.	324	765	
PD	12	4,952,063	8/27/90	Opsal et al.	356	432	
PD	13	5,042,952	827/1991	Opsal et al.	356	432	
PD	14	5,159,412	10/27/92	Willenborg et al.	356	445	
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PD	17	4,255,971	3/17/81	Rosencwaig	73	606	
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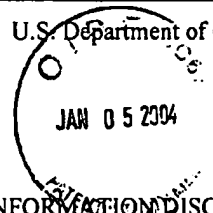
129	26	5,761,082	6/2/98	Miura-Mattausch	703	14	
129	27	4,996,659	2/26/91	Yamaguchi et al.	714	736	
130	28	6,154,280	11/2/00	Borden	356	376	
130	29	6,054,868	4/25/00	Borden et al.	324	752	
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13	31	5,877,860	3/2/99	Borden	356	376	
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13	33	5,978,074	11/2/99	Opsal et al.	356	72	
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13	44	6,281,027	9/28/01	Wei et al.	438	14	
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13	46	5,074,669	12/1/91	Opsal	356	447	
13	47	5,764,363	6/9/98	Ooki et al.	356	364	
13	48	5,657,754	8/19/97	Rosencwaig	128	633	
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13	50	4,552,510	6/11/85	Rosencwaig	374	7	
13	51	4,571,685	02/18/86	Kamoshida	364	468	

Examiner: <i>P. J. Smith</i>	Date Considered: <i>6/10/04</i>
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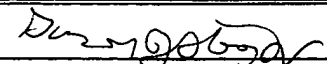
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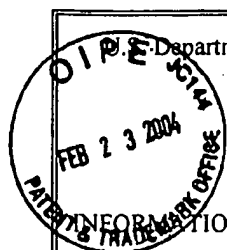
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							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
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ms	53	00/07357	3/20/2000	PCT	G01L	21/17		
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Examiner: <i>Dwight J. Smith</i>	Date Considered: <i>6/10/04</i>
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Department of Commerce, Patent and Trademark Office

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Examiner Name:	Smith, Zandra B.
Confirmation No.:	1003
Attorney Docket No.:	BOX013 US

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*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
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JS	2.	6,020,964	2/1/00	Loopstra et al.	356	500	
JS	3.	6,400,454	6/4/02	Noguchi et al.	356	237	

Foreign Patent Documents

							Translation	
		Document	Date	Country	Class	Subclass	Yes	No

Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner: <i>Dmitry G. G.</i>	Date Considered: <i>6/10/04</i>
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